

Search Notes

Application/Control No.

10/626,369

Examiner

Anthony Weier

Applicant(s)/Patent under
Reexamination

CHENG ET AL.

Art Unit

1761

SEARCHED

Class	Subclass	Date	Examiner
updated	previous search along with		
426	594, 597		
	115, 119	11/17/2006	AW

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
99	594		
222	137,145.8		
426	594, 597		
426/115, 119		11/17/2006	AW

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
PGPubText Search	11/17/2006	AW